July 2003

# FDD6690A

**FAIRCHILD** SEMICONDUCTOR

# 30V N-Channel PowerTrench<sup>o</sup> MOSFET

### **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on state resistance and yet maintain low gate charge for superior switching performance.

## Applications

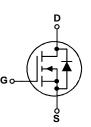
- DC/DC converter
- Motor Drives

# Features

• 46 A, 30 V 
$$R_{DS(ON)} = 12 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$$
  
 $R_{DS(ON)} = 14 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$ 

- Low gate charge
- Fast Switching Speed
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$





## Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Para	meter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage			30	V
V <sub>GSS</sub>	Gate-Source Voltage			±20	V
I <sub>D</sub>	Continuous Drain Current	@T <sub>c</sub> =25°C	(Note 3)	46	А
		@T <sub>A</sub> =25°C	(Note 1a)	12	
		Pulsed	(Note 1a)	100	
PD	Power Dissipation	@T <sub>c</sub> =25°C	(Note 3)	56	W
		@T <sub>A</sub> =25°C	(Note 1a)	3.3	
		@T <sub>A</sub> =25°C	(Note 1b)	1.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Ju	nction Temperatu	re Range	-55 to +175	°C
Therma	I Characteristics				
$R_{\theta JC}$	Thermal Resistance, Junc	tion-to-Case	(Note 1)	2.7	°C/W
$R_{\theta JA}$	Thermal Resistance, Junc	tion-to-Ambient	(Note 1a)	45	
Reia	7		(Note 1b)	96	

## Package Marking and Ordering Information

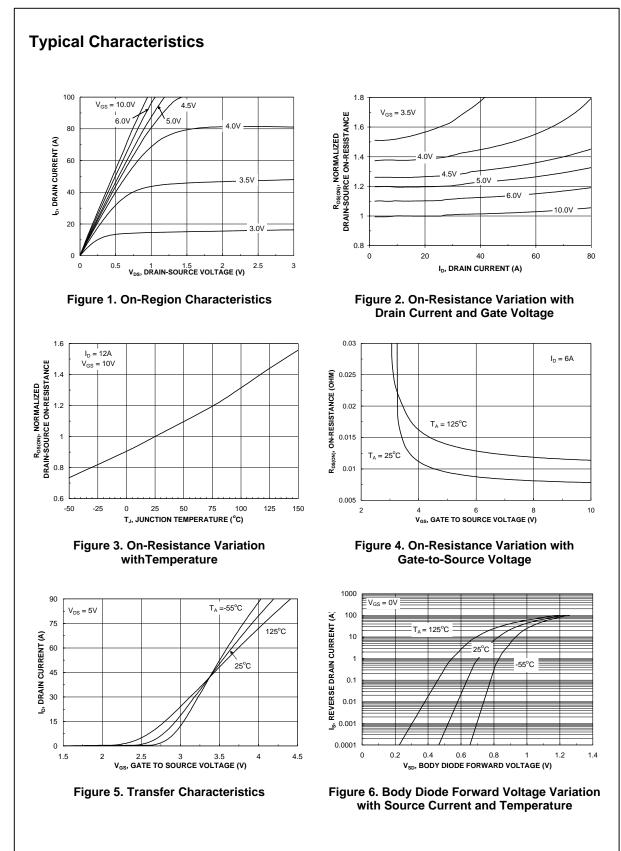
Device Marking	Device	Package	Reel Size	Tape width	Quantity
FDD6690A	FDD6690A	D-PAK (TO-252)	13"	12mm	2500 units

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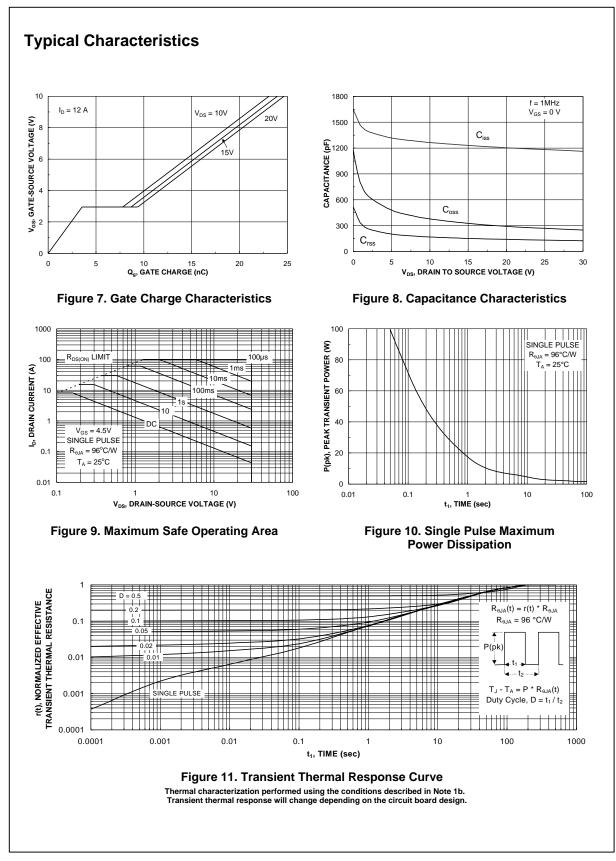
	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	urce Avalanche Ratings (Note	2)	•		•	•
E <sub>AS</sub>	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 15 \text{ V}$ , $I_D = 12 \text{ A}$			180	mJ
I <sub>AS</sub>	Drain-Source Avalanche Current	-			12	А
Off Char	acteristics			1		1
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$ , $I_D = 250 \mu A$	30			V
<u>ΔBV<sub>DSS</sub></u> ΔTJ	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$		24		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V},  V_{GS} = 0 \text{ V}$			1	μA
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V},  V_{DS} = 0 \text{ V}$			±100	nA
On Chara	acteristics (Note 2)	•				,
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	1	1.9	3	V
$\Delta V_{GS(th)}$ $\Delta T_{J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$		-5		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance			7.7 9.9 11.4	12 14 19	mΩ
I <sub>D(on)</sub>	On–State Drain Current	$V_{GS} = 10 \text{ V},  V_{DS} = 5 \text{ V}$	50			А
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V},  I_D = 12 \text{ A}$		47		S
Dynamic	Characteristics			1		
C <sub>iss</sub>	Input Capacitance			1230		pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 15 \text{ V},  V_{GS} = 0 \text{ V},$		325		pF
Crss	Reverse Transfer Capacitance	f = 1.0 MHz		150		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.5		pF
Switchin	g Characteristics (Note 2)			1		
t <sub>d(on)</sub>	<b>g Characteristics</b> (Note 2) Turn–On Delay Time			10	19	ns
t <sub>r</sub>	Turn–On Rise Time	$V_{DD} = 15 \text{ V},  I_D = 1 \text{ A},$	-	7	13	ns
t <sub>d(off)</sub>	Turn–Off Delay Time	$V_{GS} = 10 \text{ V},  R_{GEN} = 6 \Omega$		29	46	ns
t <sub>f</sub>	Turn-Off Fall Time			12	21	ns
Qq	Total Gate Charge			13	18	nC
Q <sub>qs</sub>	Gate–Source Charge	$V_{DS} = 15V, I_D = 12 A,$	-	3.5		nC
Q <sub>gd</sub>	Gate–Drain Charge	$V_{GS} = 5 V$		5.1		nC

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	urce Diode Characteristics a	nd Maximum Ratings				
ls	Maximum Continuous Drain-Source	Diode Forward Current			2.3	А
V <sub>SD</sub>	Drain–Source Diode Forward Voltage			0.76	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = 12 \text{ A}, \qquad d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		24		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge			13		nC
the drain pins.	$R_{BJC}$ is guaranteed by design while $R_{BCA}$ is determine a) $R_{BJA} = 45^{\circ}C/W \text{ w}$ 1 in <sup>2</sup> pad of 2 oz c	hen mounted on a		= 96°C/W minimum p	when moun ad.	ited
		Scale 1 : 1 on letter size paper				
Pulse Test: Pul	se Width < 300μs, Duty Cycle < 2.0%					
Maximum curr	ent is calculated as: $\sqrt{\frac{P_D}{R_{DS(ON)}}}$					

FDD6690A Rev. EW)



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Programmable A		POP™	SuperSOT™-3	

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